

BTA316X-800CT

Rev.02 - 12 September 2018

3Q Triac

Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a SOT186A "full pack" plastic package intended for use in circuits where high static and dynamic dV/dt and high dl/dt can occur. This "series CT" triac will commutate the full RMS current at the maximum rated junction temperature ($T_{j(max)} = 150$ °C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

2. Features and benefits

- 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High junction operating temperature capability (T_{j(max)} = 150 °C)
- High immunity to false turn-on by dV/dt
- High voltage capability
- Isolated mounting base package
- Less sensitive gate for very high noise immunity
- Planar passivated for voltage ruggedness and reliability
- Triggering in three quadrants only

3. Applications

- Applications subject to high temperature (T_{j(max)} = 150 °C)
- Electronic thermostats
- High power motor controls e.g. washing machines and vacuum cleaners
- Rectifier-fed DC inductive loads e.g. DC motors and solenoids
- Refrigeration and air conditioning compressor

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit
Absolute	maximum rating			
V_{DRM}	repetitive peak off-state voltage		800	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _h ≤ 67 °C; <u>Fig. 1; Fig. 2; Fig. 3</u>	16	A
I _{TSM}	non-repetitive peak on- state current	full sine wave; t _p = 20 ms; T _{j(init)} = 25 °C; <u>Fig. 4; Fig. 5</u>	140	A
		full sine wave; t_p = 16.7 ms; $T_{j(init)}$ = 25 °C	150	А
Tj	junction temperature		150	°C

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Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static cha	racteristics	· · · · · · · · · · · · · · · · · · ·	•				
I _{GT}	gate trigger current	V_{D} = 12 V; I _T = 0.1 A; T2+ G+ T _j = 25 °C; <u>Fig. 7</u>		2	-	35	mA
		V_{D} = 12 V; I _T = 0.1 A; T2+ G- T _j = 25 °C; <u>Fig. 7</u>		2	-	35	mA
		$V_{D} = 12 \text{ V; } I_{T} = 0.1 \text{ A; } \text{T2- G-} $ $T_{j} = 25 \text{ °C; } \text{Fig. 7}$		2	-	35	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	35	mA
V _T	on-state voltage	I _T = 18 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.3	1.5	V
Dynamic	characteristics	· · · · · · · · · · · · · · · · · · ·					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		500	-	-	V/µs
		V_{DM} = 536 V; T _j = 150 °C; (V _{DM} = 67% of V _{DRM}); exponential waveform; gate open circuit		200	-	-	V/µs
dl _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V}; \text{T}_\text{j} = 150 ^\circ\text{C}; \text{I}_{\text{T(RMS)}} = 16 \text{ A}; $ $dV_{\text{com}}/dt = 20 \text{ V/}\mu\text{s}; \text{ gate open circuit}; $ snubberless condition		8	-	-	A/ms

5. Pinning information

Table 2. Pinning information							
Pin	Symbol	Description	Simplified outline	Graphic symbol			
1	T1	main terminal 1	mb	T2T1			
2	T2	main terminal 2		G sym051			
3	G	gate		oymoo r			
mb	n.c.	mounting base; isolated					

6. Ordering information

Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
BTA316X-800CT	TO-220F	Plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 'full pack'	SOT186A	

7. Marking

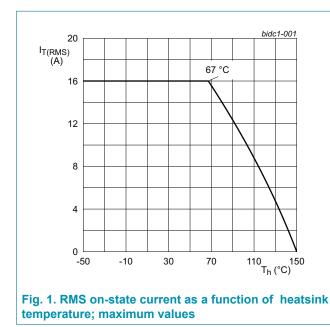
Table 4. Marking codes			
Type number		Marking codes	
BTA316X-800CT		BTA316X-800CT	
BTA316X-800CT	All information provided in this documer	nt is subject to legal disclaimers.	[©] WeEn Semiconductors Co., Ltd. 2018. All rights reserved

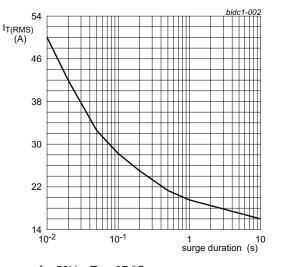
8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
V _{drm}	repetitive peak off-state voltage		800	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _h ≤ 67 °C; <u>Fig. 1</u> ; <u>Fig. 2; Fig. 3</u>	16	A
I _{TSM}	non-repetitive peak on- state current	full sine wave; t_p = 20 ms; $T_{j(init)}$ = 25 °C; Fig. 4; Fig. 5	140	A
		full sine wave; t_p = 16.7 ms; $T_{j(init)}$ = 25 °C	150	А
l ² t	l ² t for fusing	t _p = 10ms; sine wave	98	A ² s
dl⊤/dt	rate of rise of on-state current	I _G = 70mA	100	A/µs
I _{GM}	peak gate current		2	А
P _{GM}	peak gate power		5	W
P _{G(AV)}	average gate power	over any 20 ms period	0.5	W
T _{stg}	storage temperature		-40 to 150	°C
T _j	junction temperature		150	°C

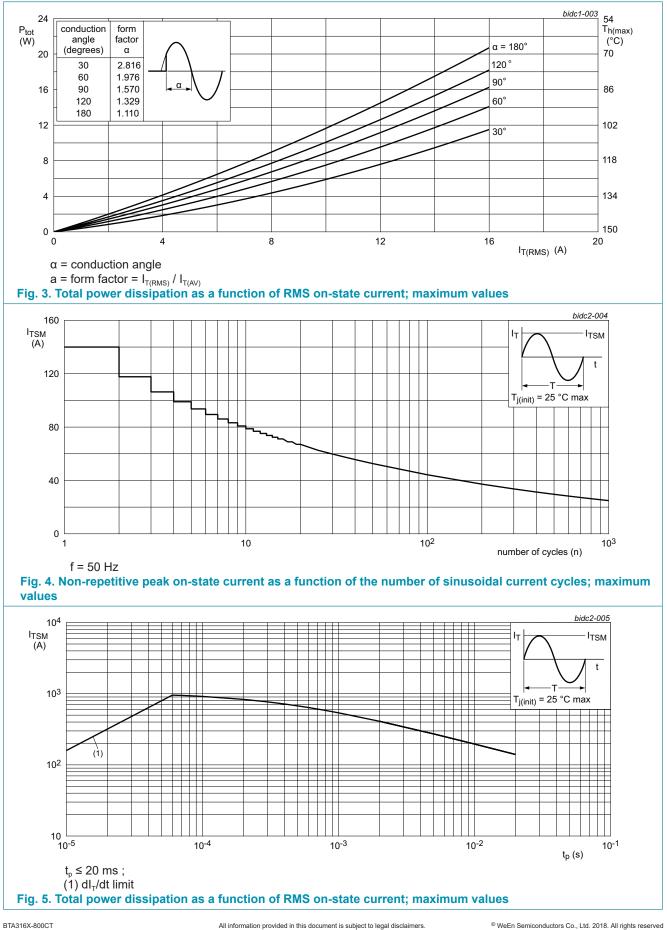




f = 50Hz; $T_h = 67$ °C Fig. 2. RMS on-state current as a function of surge duration; maximum values

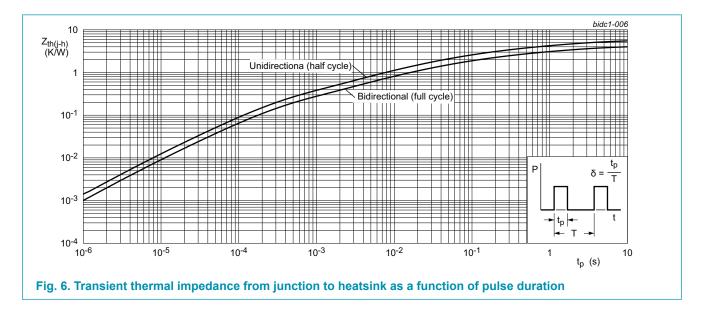
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9. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R _{th(j-h)}	thermal resistance from junction to	with heatsink compound; Fig. 6	-	-	4	K/W
	heatsink	without heatsinkcompound; Fig. 6	-	-	5.5	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient free air	in free air	-	55	-	K/W



10. Isolation characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{\text{isol}(\text{RMS})}$	RMS isolation voltage	50 Hz \leq f \leq 60 Hz; RH \leq 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
C _{isol}	isolation capacitance	from cathode to external heatsink	-	10	-	PF

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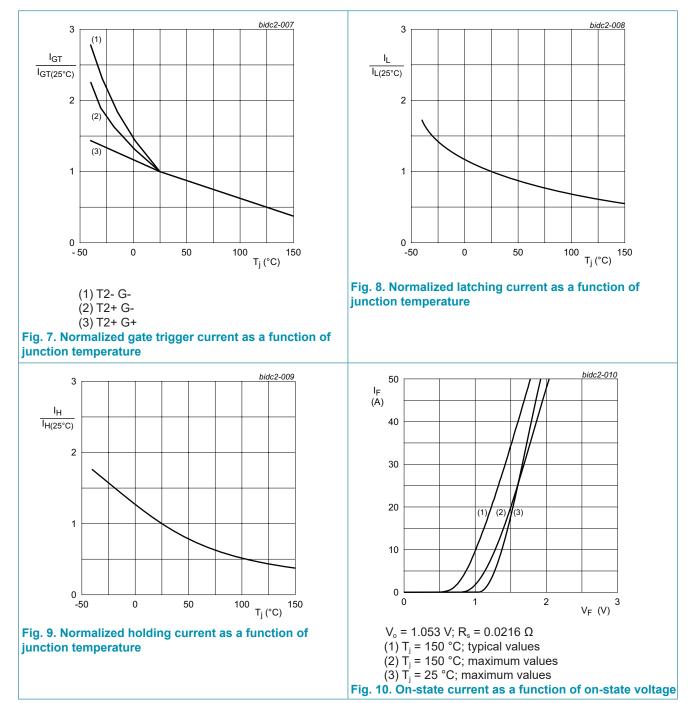
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11. Characteristics

Parameter	Conditions	Min	Typ	Max	Unit
racteristics					
gate trigger current	$V_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}; \text{ T2+ G+};$ $T_{j} = 25 \text{ °C}; \text{ Fig. 7}$	2	-	35	mA
	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2+ G-};$ T _j = 25 °C; <u>Fig. 7</u>	2	-	35	mA
	$V_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}; \text{ T2- G-};$ $T_{j} = 25 \text{ °C}; \text{ Fig. 7}$	2	-	35	mA
latching current	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2+ G+};$ $\text{T}_{j} = 25 \text{ °C}; \text{ Fig. 8}$	-	-	50	mA
	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2+ G-};$ $\text{T}_{j} = 25 \text{ °C}; \text{ Fig. 8}$	-	-	60	mA
	$V_{D} = 12 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T2- G-};$ $\text{T}_{j} = 25 ^{\circ}\text{C}; \text{ Fig. 8}$	-	-	50	mA
holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	-	35	mA
on-state voltage	I _T = 18 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.3	1.5	V
gate trigger voltage	$V_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}; T_{j} = 25 \text{ °C};$ Fig. 11	-	0.8	1	V
	$V_{D} = 400 \text{ V}; \text{ I}_{T} = 0.1 \text{ A}; \text{ T}_{j} = 150 \text{ °C};$ Fig. 11	0.25	0.4	-	V
off-state current	V _D = 800 V; T _j = 25 °C	-	-	10	μA
	V _D = 800 V; T _j = 150 °C	-	-	2	mA
characteristics	· · · ·		·		
rate of rise of off-state voltage	V_{DM} = 536 V; T _j = 125 °C; (V _{DM} = 67% of V _{DRM}); exponential waveform; gate open circuit	500	-	-	V/µs
	V_{DM} = 536 V; T _j = 150 °C; (V _{DM} = 67% of V _{DRM}); exponential waveform; gate open circuit	200	-	-	V/µs
rate of change of commutating current	$V_D = 400 \text{ V}; \text{ T}_j = 150 \text{ °C}; \text{ I}_{T(RMS)} = 16 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ gate open circuit};$ snubberless condition	8	-	-	A/ms
	racteristics gate trigger current gate trigger current latching current holding current on-state voltage gate trigger voltage gate trigger voltage off-state current characteristics rate of rise of off-state voltage voltage rate of change of	racteristicsgate trigger current $V_D = 12 V; I_T = 0.1 A; T2+ G+; T_1 = 25 °C; Fig. TV_D = 12 V; I_T = 0.1 A; T2+ G-; T_1 = 25 °C; Fig. TV_D = 12 V; I_T = 0.1 A; T2- G-; T_1 = 25 °C; Fig. TV_D = 12 V; I_T = 0.1 A; T2+ G+; T_1 = 25 °C; Fig. 8V_D = 12 V; I_T = 0.1 A; T2+ G+; T_1 = 25 °C; Fig. 8V_D = 12 V; I_T = 0.1 A; T2+ G-; T_1 = 25 °C; Fig. 8V_D = 12 V; I_T = 0.1 A; T2- G-; T_1 = 25 °C; Fig. 8V_D = 12 V; I_T = 0.1 A; T2- G-; T_1 = 25 °C; Fig. 8N_D = 12 V; I_T = 0.1 A; T2- G-; F_1 = 25 °C; Fig. 9on-state voltageI_T = 18 A; T_1 = 25 °C; Fig. 10gate trigger voltageV_D = 12 V; I_T = 0.1 A; T_1 = 25 °C; Fig. 10off-state currentV_D = 12 V; I_T = 0.1 A; T_1 = 25 °C; Fig. 10off-state currentV_D = 800 V; I_T = 0.1 A; T_1 = 150 °C; Fig. 11V_D = 800 V; T_1 = 150 °Cvoltagerate of rise of off-statevoltageV_{DM} = 536 V; T_1 = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuitV_{DM} = 536 V; T_1 = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuitrate of change of commutating currentV_D = 400 V; T_1 = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit$	racteristics gate trigger current $V_D = 12 V; I_T = 0.1 A; T2 + G; T_1 = 25 °C; Fig. T$ 2 $V_D = 12 V; I_T = 0.1 A; T2 + G; T_1 = 25 °C; Fig. T$ 2 $V_D = 12 V; I_T = 0.1 A; T2 + G; T_1 = 25 °C; Fig. T$ 2 Iatching current $V_D = 12 V; I_T = 0.1 A; T2 + G; T_1 = 25 °C; Fig. T$ 2 $V_D = 12 V; I_T = 0.1 A; T2 + G; T_1 = 25 °C; Fig. 8$ - - $V_D = 12 V; I_T = 0.1 A; T2 + G; T_1 = 25 °C; Fig. 8$ - - $V_D = 12 V; I_T = 0.1 A; T2 + G; T_1 = 25 °C; Fig. 8$ - - $V_D = 12 V; I_T = 0.1 A; T2 - G; T_1 = 25 °C; Fig. 8$ - - $V_D = 12 V; I_T = 0.1 A; T2 - G; T_1 = 25 °C; Fig. 9$ - - on-state voltage $I_T = 18 A; T_1 = 25 °C; Fig. 9$ - - on-state voltage $I_T = 18 A; T_1 = 25 °C; Fig. 10$ - - gate trigger voltage $V_D = 12 V; I_T = 0.1 A; T_1 = 150 °C; Fig. 10$ - - off-state current $V_D = 12 V; I_T = 0.1 A; T_1 = 25 °C; Fig. 10$ - - $V_D = 400 V; I_T = 10.1 A; T_1 = 150 °C; Fig. 10$ - - - off-state current $V_D = 800 V; T_1 = 150 °C; Fig. 10$ - - $V_$	$\begin{tabular}{ c c c c c c } \hline racteristics & $$$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$

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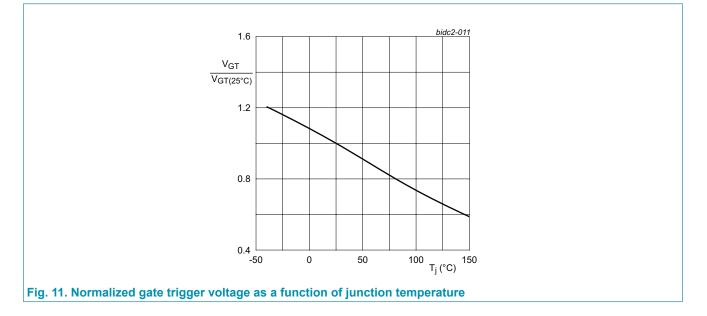
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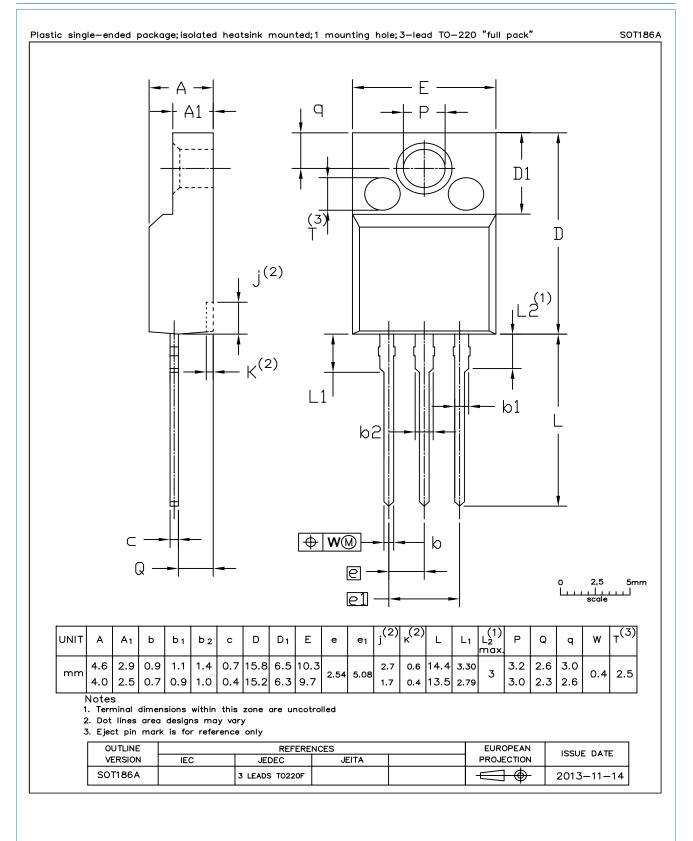
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12. Package outline



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13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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